



PTO/SB/08A/B (09-06)

Approved for use through 03/31/2007. OMB 0651-0031

U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

<b>Substitute for form 1449/PTO</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)		<b>Complete if Known</b>			
		Application Number	09/735,983-Conf. #5697		
		Filing Date	December 13, 2000		
		First Named Inventor	Seth Haberman		
		Art Unit	2611		
		Examiner Name	H. V. Tran		
Sheet	1	of	2	Attorney Docket Number	2000522.00123US2

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)				
/HT/	AA*	US-5,550,735		08-27-1996	Slade et al.	
	AB*	US-5,585,838		12-17-1996	Lawler et al.	
	AC*	US-5,652,615		07-29-1997	Bryant et al.	
	AD*	US-5,758,259		05-26-1998	Lawler	
	AE*	US-5,805,974		09-08-1998	Hite et al.	
	AF*	US-5,873,068		02-16-1999	Beaumont et al.	
	AG*	US-20010013124-A1		08-09-2001	KLOSTERMAN et al.	
	AH*	US-20020026359-A1		02-28-2002	Long et al.	
	AI*	US-6,357,042-A1		03-12-2002	Srinivasan et al.	
	AJ*	US-6,360,234-A1		03-19-2002	Jain et al.	
	AK*	US-20020056093-A1		05-09-2002	Kunkel et al.	
	AL*	US-20020057336-A1		05-16-2002	Gaul et al.	
	AM*	US-6,408,278		06-18-2002	Carney et al.	
	AN*	US-20020083443-A1		06-27-2002	Eldering et al.	
	AO*	US-6,457,010		09-24-2002	Eldering et al.	
	AP*	US-6,463,444		10-08-2002	Jain et al.	
	AQ*	US-6,502,076		12-31-2002	Smith	
	AR*	US-6,567,980		05-20-2003	Jain et al.	
	AS*	US-6,574,793		06-03-2003	Ngo et al.	
	AT*	US-20030110500-A1		06-12-2003	Rodriguez	
	AU*	US-6,588,013		07-01-2003	Lumley et al.	
	AV*	US-6,601,237		07-29-2003	Ten Kate et al.	
	AW*	US-20030177503-A1		09-18-2003	Sull et al.	
	AX*	US-6,671,880-A1		12-30-2003	Shah-Nazaroff et al.	
	AY*	US-6,681,395		01-20-2004	Nishi et al.	
	AZ*	US-20040025180-A1		02-05-2004	Begeja et al.	
	AA1*	US-6,694,482		02-17-2004	Arellano et al.	
	AB1*	US-6,698,020		02-24-2004	Zigmond et al.	
	AC1*	US-6,735,628-A1		05-11-2004	Eyal	
	AD1*	US-20040111742-A1		06-10-2004	Hendricks et al.	
	AE1*	US-20040136698-A1		07-15-2004	Mock	
	AF1*	US-6,850,252		02-01-2005	Hoffberg	
	AG1*	US-6,857,024		02-15-2005	Chen et al.	
	AH1*	US-6,877,134		04-05-2005	Fuller et al.	
	AI1*	US-20050086692-A1		04-21-2005	Dudkiewicz et al.	
	AJ1*	US-20050086691-A1		04-21-2005	Dudkiewicz et al.	
	AK1*	US-20050166224-A1		07-28-2005	Ficco	

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)					

Examiner Signature	/Hai Tran/ (04/02/2007)	Date Considered	
-----------------------	-------------------------	--------------------	--

6016626

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Use as many sheets as necessary)</i>				<b>Complete if Known</b>	
				Application Number	09/735,983-Conf. #5697
				Filing Date	December 13, 2000
				First Named Inventor	Seth Haberman
				Art Unit	2611
				Examiner Name	H. V. Tran
Sheet	2	of	2	Attorney Docket Number	2000522.00123US2

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. \* CITE NO.: Those application(s) which are marked with an single asterisk (\*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature	/Hai Tran/ (04/02/2007)	Date Considered	
--------------------	-------------------------	-----------------	--